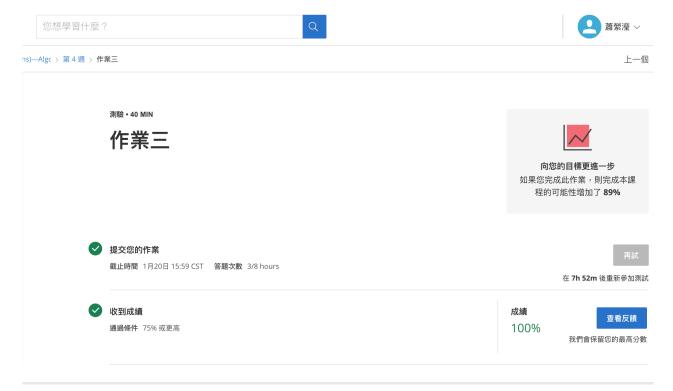
# **Machine Learning Foundation Hw3**

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#### **Problem 1**

**Score**: 100 %



# **Problem 2**

Prove  $err(w) = max(0, -yw^Tx)$  results in PLA .

The update on **PLA** algorithm  $: w_{t+1} \leftarrow w_t + [y 
eq sign(w^Tx)]yx$ 

$$abla_w err(w) = egin{cases} rac{\delta - y w^T x}{\delta w}, & if - y w^T x > 0 \ 0, & if - y w^T x < 0 \end{cases}$$

$$= egin{cases} -yx, & if\ yw^Tx < 0 \ 0, & if\ yw^Tx > 0 \end{cases}$$

$$=-[y 
eq sign(w^Tx)]yx$$

It's obvious to see that  $w_{t+1} \leftarrow w_t + [y 
eq sign(w^Tx)]yx$ 

$$=w_t+\eta(-
abla_werr(w)),$$
 when  $\eta=1$ 

### **Problem 3**

To minimize  $\hat{E_2}(\Delta u, \Delta v)$ , we would like to find  $\Delta u, \Delta v$  such that  $\nabla \hat{E_2}(\Delta u, \Delta v) = 0$ 

$$abla \hat{E_2}(\Delta u, \Delta v) = 
abla (E(u,v) + (\Delta u, \Delta v) 
abla E(u,v) + rac{1}{2} ((\Delta u, \Delta v) (
abla E(u,v)))^2)$$

$$=
abla E(u,v)+(\Delta u,\Delta v)(
abla^2(u,v))=0$$

Therefore, 
$$(\Delta u, \Delta v) = -(
abla^2 E(u,v))^{-1} 
abla E(u,v)$$

### **Problem 4**

 $likelihood(w) \propto \prod_{n=1}^{N} h_{y_n}(x_n) \propto \ln \prod_{n=1}^{N} h_{y_n}(x_n)$ 

 $\max_{w} likelihood(w) \propto \prod_{n=1}^{N} h_{y_n}(x_n)$ 

 $\max_w likelihood(w) 
ightarrow \min_w rac{1}{N} \Sigma_{n=1}^N - \ln(h_{y_n}(x_n))$ 

$$ightarrow \min_w rac{1}{N} \Sigma_{n=1}^N \ln(\Sigma_{i=1}^k e^{w_i^T x_n}) - ln(e^{w_{y_n}^T x_n})$$

$$ightarrow \min_w rac{1}{N} \Sigma_{n=1}^N \ln(\Sigma_{i=1}^k e^{w_i^T x_n}) - w_{y_n}^T x_n$$

Therefore,  $E_{in} = rac{1}{N}\Sigma_{n=1}^N \ln(\Sigma_{i=1}^k e^{w_i^T x_n}) - w_{y_n}^T x_n$ 

## **Problem 5**

$$E_{in}(w_{lin}) = \min_{w} rac{1}{N+K} (\Sigma_{n=1}^{N}(y_n - w^T x_n) + \Sigma_{k=1}^{K}( ilde{y}_k - w^T ilde{x}_k))$$

$$=\min_{w}rac{1}{N+K}[(w^TX^TXw+2w^TX^Ty+y^Ty)+(w^T ilde{X}^T ilde{X}w+2w^T ilde{X}^T ilde{y}+ ilde{y}^T ilde{y})]$$

$$\Rightarrow 
abla E_{in}(w_{lin}) = rac{2}{N+K}(x^TXw_{lin} - X^Ty + ilde{X}^T ilde{X}w_{lin} - ilde{X}^T ilde{y}) = 0$$

$$\Rightarrow (X^TX + { ilde{X}}^T{ ilde{X}})w_{lin} = X^Ty + { ilde{X}}^T{ ilde{y}}$$

$$\Rightarrow w_{lin} = (X^TX + { ilde{X}}^T{ ilde{X}})^{-1}(X^Ty + { ilde{X}}^T{ ilde{y}})$$

# **Problem 6**

From above, we know the optimal solution  $w_{reg} \leftarrow (Z^TZ + \lambda I)^{-1}Z^Ty$ 

That is, 
$$ilde{X}^T ilde{X}=\lambda I, ilde{X}^T ilde{y}=0$$

$$\Rightarrow \tilde{X} = \sqrt{\lambda}I, \tilde{y} = 0$$

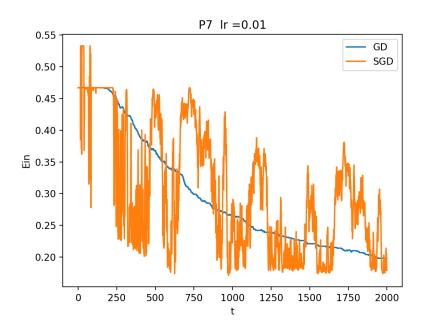
# **Problem 7**

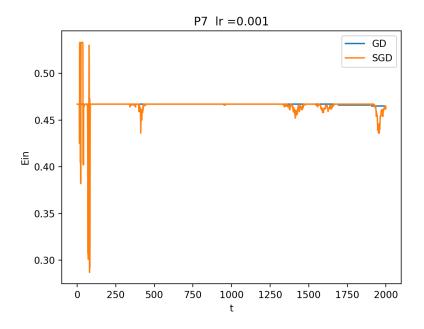
Finding:

• vibration: It is clearly to see the vibration of SGD is much bigger than GD. We can infer that

it is owing to SGD only trains 1 data each time, so each update can't lower the total error effectively.

•  $\eta$ : Big  $\eta$  (lr=0.01) can lower total error rate faster than small one lr=0.001.

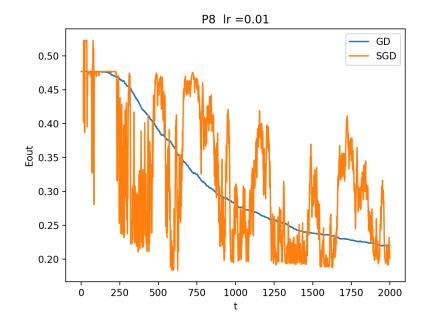


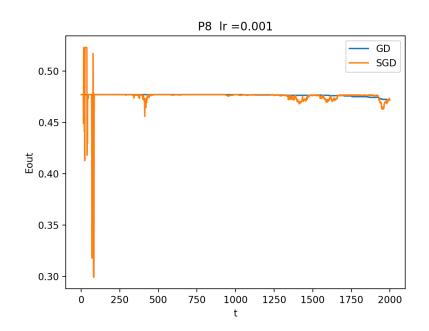


# **Problem 8**

#### Finding:

• **pattern**: The pattern of Eout is similar to Ein, while the value of Eout seems to be a little bit higher than Ein. We can infer that  $hw3\_train. dat$  and  $hw3\_test. dat$  has high correlation. Because Ein is proportional to Eout under the same hypothesis.





# **Bonus**

(a)

$$egin{aligned} X^TXw_{lin} &= X^T(U\Gamma V^T)(V\Gamma^{-1}U^Ty) \ &= X^TU\Gamma(V^TV)\Gamma^{-1}U^Ty \ (\because commutation\ law) \ &= X^TU(\Gamma\Gamma^{-1})U^Ty \ (\because V^TV = I
ho) \ &= X^T(UU^T)y \ (\because \Gamma\Gamma^{-1} = I
ho) \ &= X^Ty \ (\because U^TU = I
ho) \end{aligned}$$